| Applicant(s)/Patent under Reexamination APPEL ET AL. | | INTERNATIONAL CLASSIFICATION | NON-CLAIMED | 3 B 0 1 D 63 / 00 | | | | Total Claims Allowed: | O.G. O.G. Print Claim(s) Print |
|------------------------------------------------------------|-----------------------------------|------------------------------|-------------|-------------------|--------------------|--------------------------|---------------|-----------------------|--------------------------------------|
| Applicant(s Reexamina APPEL ET | Art Unit | INTERNATION | CLAIMED | B 0 1 D 63/16 | T | | | W W | 9/30/06 (Date) |
| Application/Control No. | Examiner Menon, Krishnan S | IAL | SUBCLASS | 321.67 | RENCE(S) | SUBCLASS PER BLOCK) | 321.87 | KIM | Krishnan S. Menon (Primary Examiner) |
| Issue Classification | | ORIGINAL | CLASS | | CROSS REFERENCE(S) | SUBCLASS (ONE SUBCLASS P | 10 321.68 650 | yaminer) (Date) | Legip Instruments Examinent (Date) |
| İ | | | | 210 | | CLASS | 210 | (Assistant Examiner) | (Legigalinstrum) |

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